

**1.0mΩ, 30V, N-Channel Power MOSFET**
**SRT03N010LD56TR-G**
**General Description**

The Sanrise SRT03N010LD56TR-G uses advanced split gate trench technology. It has extremely low on resistance, low gate charge and fast switching time. This device is ideal for Motor driver, BMS, DCDC converter and power management.

The SRT03N010LD56TR-G break down voltage is 30V and it has a high rugged avalanche characteristic.

The SRT03N010LD56TR-G is available in PDFN5\*6 package.

**Features**

- Ultra Low  $R_{DS(ON)} = 0.8m\Omega @ V_{GS} = 10V$ .
- Ultra Low Gate Charge,  $Q_g=90nC$  typ.
- Fast switching capability
- Robust design with better EAS performance
- Non-automotive Qualified

**Application**

- Server / Telecom
- High Power Supply, such as DCDC converter
- Motor Driver, such as E-Tools
- BMS

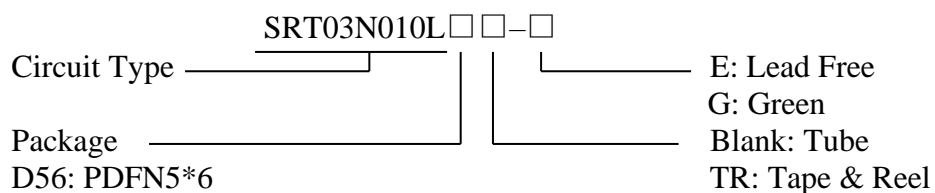
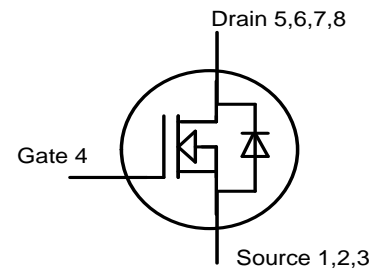
**Ordering Information**

**Symbol**


Figure 1 Symbol of SRT03N010LD56TR-G

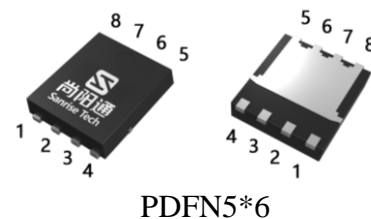
**Package Type**


Figure 2 Package Type of SRT03N010LD56TR-G

Package	Part Number		Marking ID		Packing Type
	Lead Free	Green	Lead Free	Green	
PDFN5*6	SRT03N010LD56TR-E	SRT03N010LD56TR-G	SRT03N010LD56E	SRT03N010LD56G	Tape & Reel

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### Absolute Maximum Ratings

Parameter		Symbol	Rating	Unit
Drain-Source Voltage		$V_{DSS}$	30	V
Gate-Source Voltage		$V_{GSS}$	±20	V
Continuous Drain Current	$T_C=25^{\circ}C$	$I_D$	284	A
	$T_C=100^{\circ}C$		180	
Pulsed Drain Current (Note 2)		$I_{DM}$	892	A
Power Dissipation ( $T_C = 25^{\circ}C$ )		$P_D$	178	W
Avalanche Energy, Single Pulse (Note 3)		$E_{AS}$	180	mJ
Avalanche Current, Repetitive (Note 2)		$I_{AR}$	60.0	A
Continuous Diode Forward Current		$I_S$	284	A
Diode Pulse Current		$I_{S,PULSE}$	892	A
Operating Junction Temperature		$T_J$	150	$^{\circ}C$
Storage Temperature		$T_{STG}$	-55 to 150	$^{\circ}C$
Lead Temperature (Soldering, 10 sec)		$T_{LEAD}$	260	$^{\circ}C$

Note:

- Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
- Repetitive Rating: Pulse width limited by maximum junction temperature
- $I_{AS}= 60.0A$ ,  $V_{DD}= 30V$ ,  $R_G= 25\Omega$ , Starting  $T_J= 25^{\circ}C$

### Thermal Characteristics

Parameter		Symbol	Min	Typ	Max	Unit
Thermal Resistance, Junction-to-Case	PDFN5*6	$R_{thJC}$		0.5	0.7	$^{\circ}C/W$
Thermal Resistance, Junction-to-Ambient	PDFN5*6	$R_{thJA}$			62	

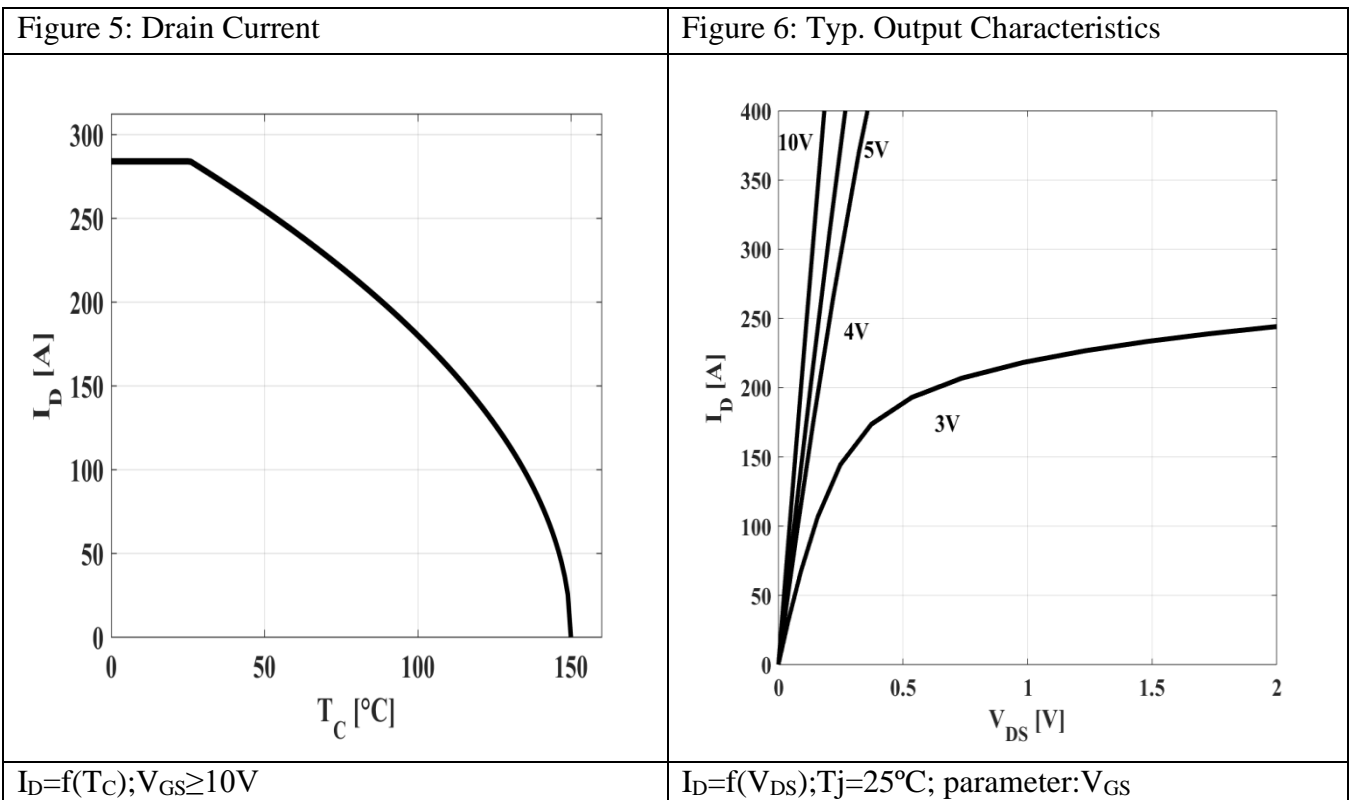
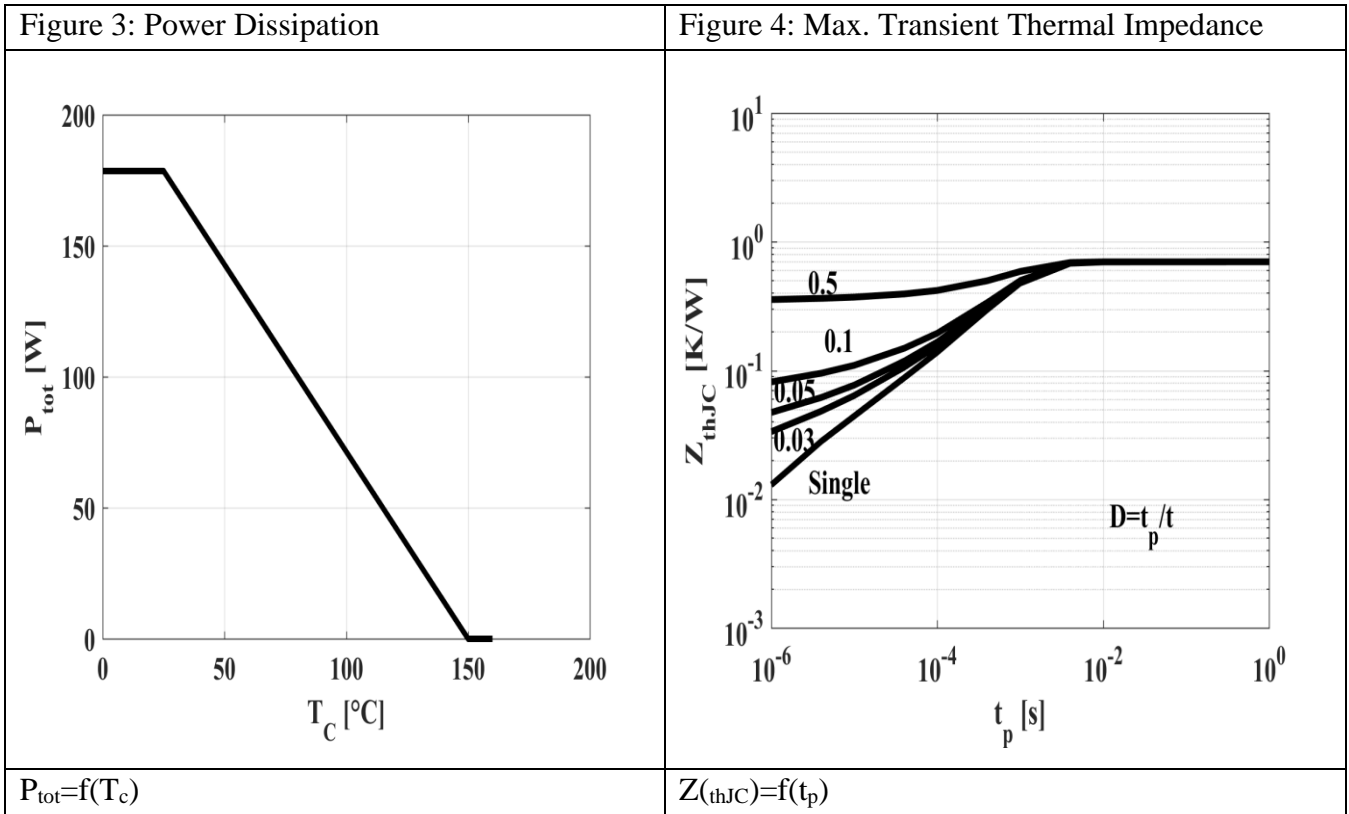
**Electrical Characteristics**

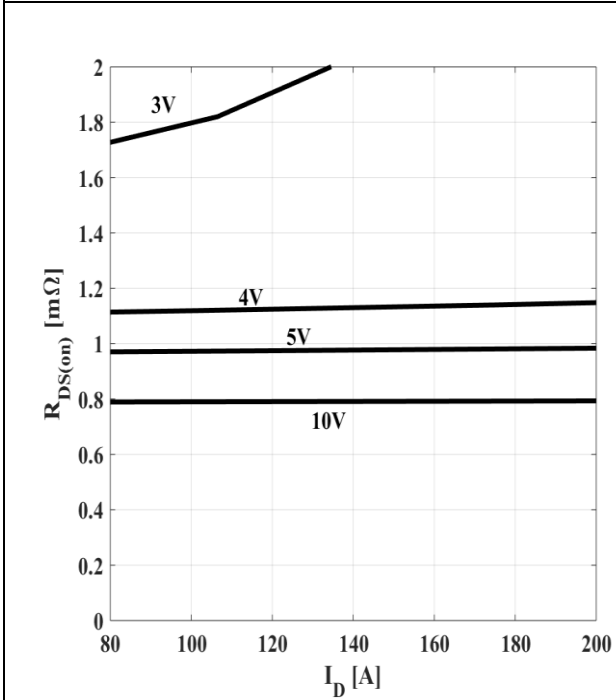
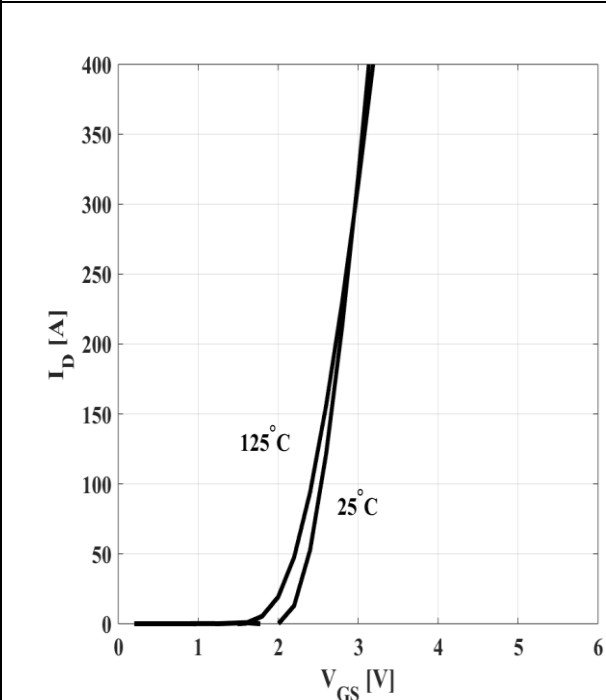
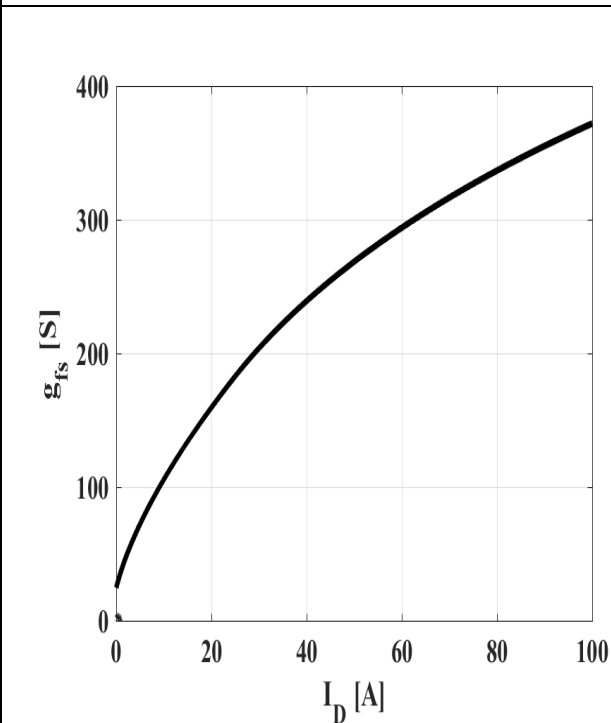
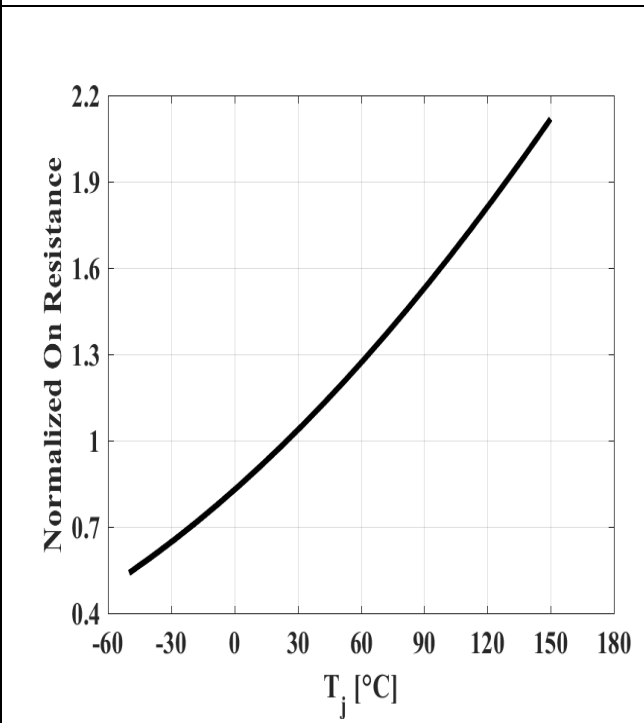
 T<sub>J</sub> = 25 °C, unless otherwise specified.

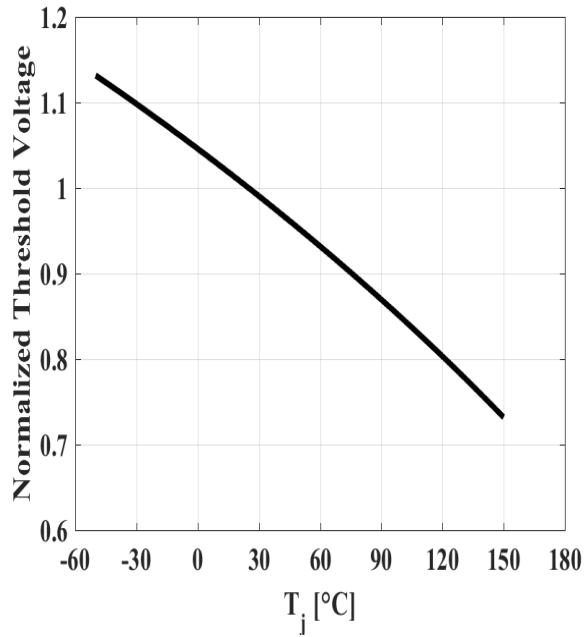
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Statistic Characteristics</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			1	uA
Gate-Body Leakage Current	Forward	I <sub>GSSF</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V		100	nA
	Reverse	I <sub>GSSR</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V		-100	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =0.25mA	1.0	1.5	2.0	V
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =100A		0.8	1.0	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A		1.05	1.4	
Gate Resistance (Note 4)	R <sub>G</sub>	f=1MHz, Open Drain	0.8	1.8	2.8	Ω
<b>Dynamic Characteristics</b>						
Input Capacitance (Note 4)	C <sub>ISS</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz	5.1	7.2	9.3	nF
Output Capacitance (Note 4)	C <sub>OSS</sub>		2.1	3.0	3.9	nF
Reverse Transfer Capacitance (Note 4)	C <sub>RSS</sub>		150	550	950	pF
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =15V, I <sub>D</sub> =100A R <sub>G</sub> =1.6Ω, V <sub>GS</sub> =10V		12		ns
Rise Time	t <sub>r</sub>			9		
Turn-off Delay Time	t <sub>d(off)</sub>			50		
Fall Time	t <sub>f</sub>			9		
<b>Gate Charge Characteristics</b>						
Gate to Source Charge	Q <sub>gs</sub>	V <sub>DD</sub> =15V, I <sub>D</sub> =100A V <sub>GS</sub> =0 to 10V		17		nC
Gate to Drain Charge	Q <sub>gd</sub>			16		
Gate Charge Total (Note 4)	Q <sub>g</sub>			90	135	
Gate Plateau Voltage	V <sub>plateau</sub>			2.8		V
<b>Reverse Diode Characteristics</b>						
Drain-Source Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>SD</sub> =100A		0.86	1.1	V
Reverse Recovery Time (Note 4)	t <sub>rr</sub>	V <sub>R</sub> =15V, I <sub>F</sub> =100A dI <sub>F</sub> /dt=100A/us		55	110	ns
Reverse Recovery Charge (Note 4)	Q <sub>rr</sub>			70	140	nC
Peak Reverse Recovery Current (Note 4)	I <sub>rrm</sub>			2.5		A

Note:

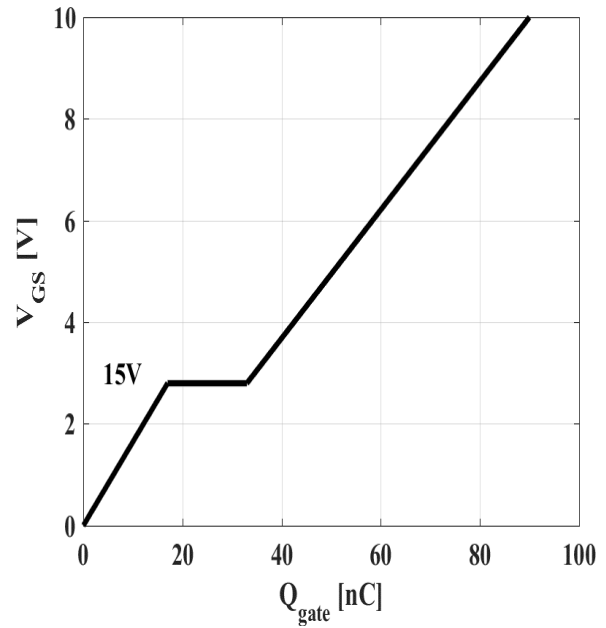
4. Defined by design. Not subject to production test.

**Typical Performance Characteristics**


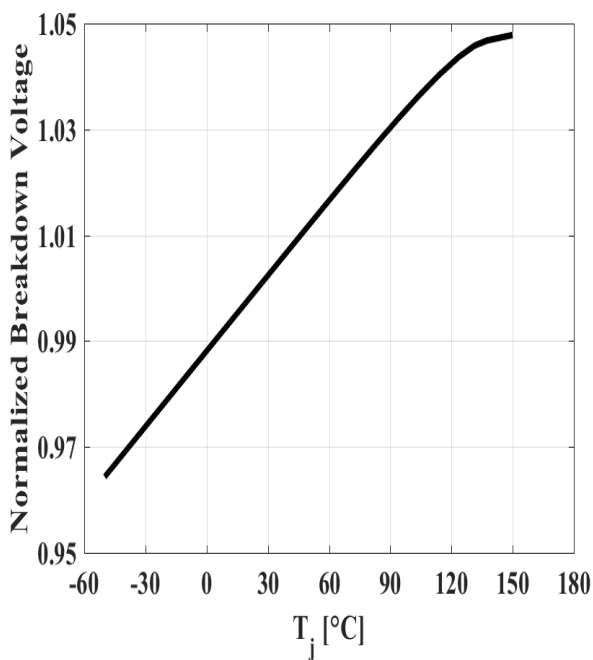
**Figure7: Typ. Drain-Source On-State Resistance**

 $R_{DS(ON)}=f(I_D); T_j=25^{\circ}C$ ; parameter:  $V_{GS}$ 
**Figure8: Typ. Transfer Characteristics**

 $I_D=f(V_{GS}); |V_{DS}|>2|I_D|R_{DS(on)max}$ ; parameter:  $T_j$ 
**Figure 9: Typ. Forward Transconductance**

 $g_{fs}=f(I_D)$ ;  $T_j=25^{\circ}C$ 
**Figure 10: Typ. Drain-Source On-State Resistance**

 $R_{DS(ON)}=f(T_j); I_D=100A; V_{GS}=10V$

**Figure 11: Typ. Gate Threshold Voltage**


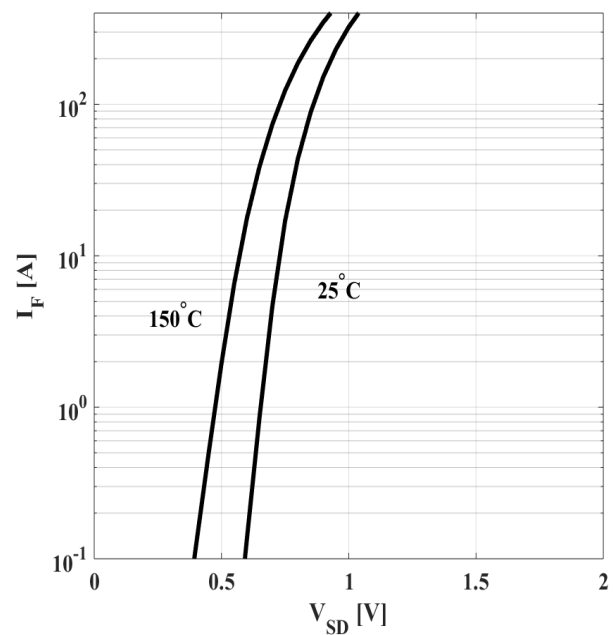
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}; I_{DS} = 250\mu A$$

**Figure 12: Typ. Gate Charge**


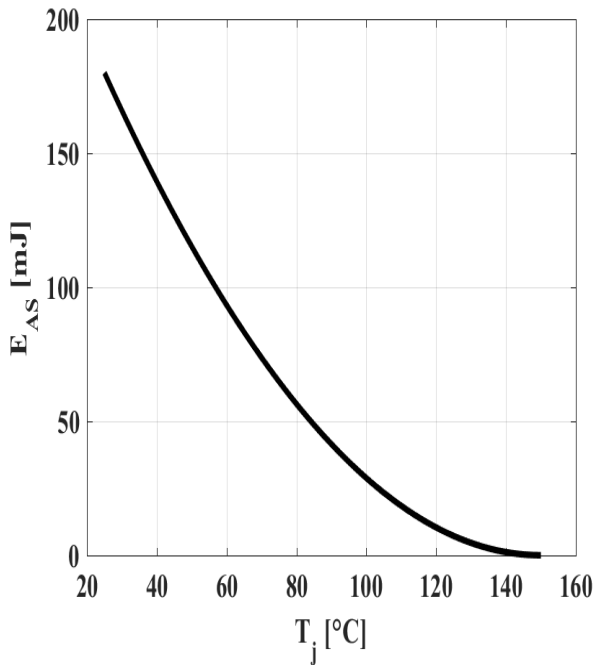
$$V_{GS} = f(Q_{gate}), I_D = 50A \text{ pulsed}$$

**Figure 13: Drain-Source Breakdown Voltage**


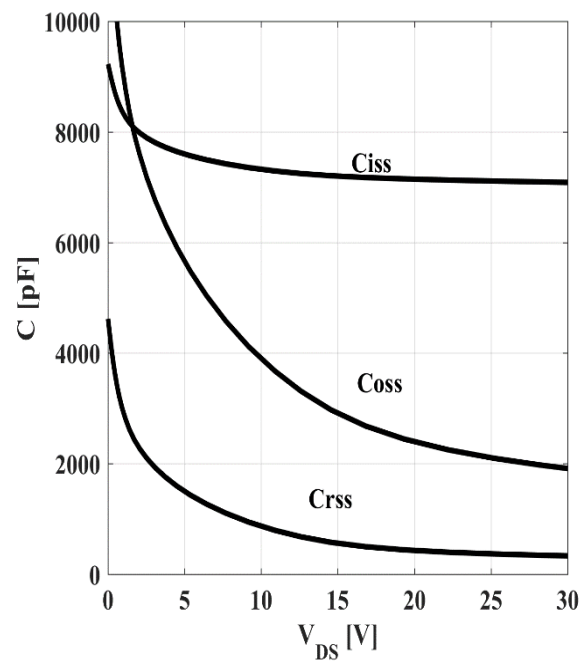
$$V_{BR(DSS)} = f(T_j); I_D = 1mA$$

**Figure 14: Forward Characteristics of Reverse Diode**


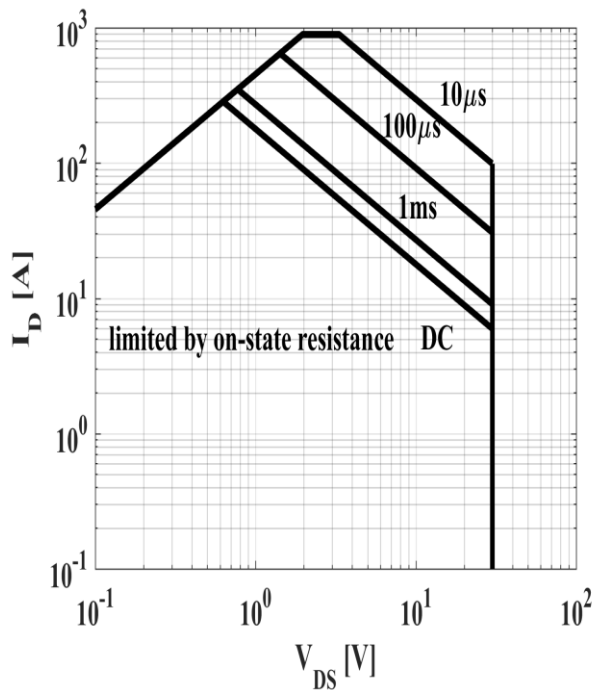
$$I_F = f(V_{SD}); \text{parameter: } T_j$$

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**Figure 15: Avalanche Energy**


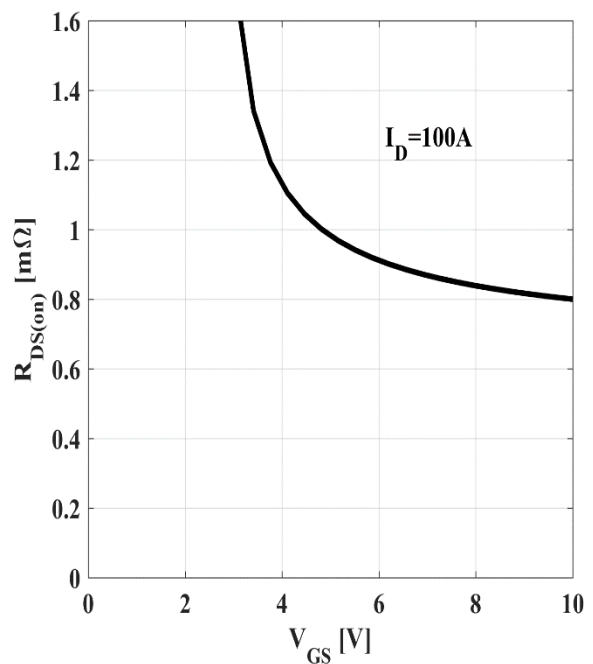
$$E_{AS}=f(T_j); I_D=60.0A; V_{DD}=15V$$

**Figure 16: Typ. Capacitances**


$$C=f(V_{DS}); V_{GS}=0; f=1MHz$$

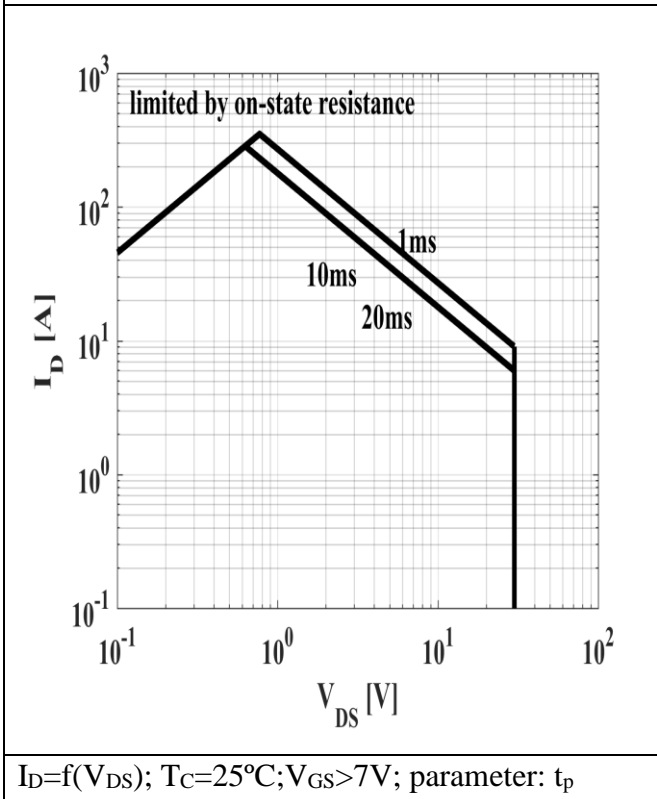
**Figure 17: Safe Operating Area 1**


$$I_D=f(V_{DS}); T_C=25^{\circ}C; V_{GS}>7V; \text{parameter: } t_p$$

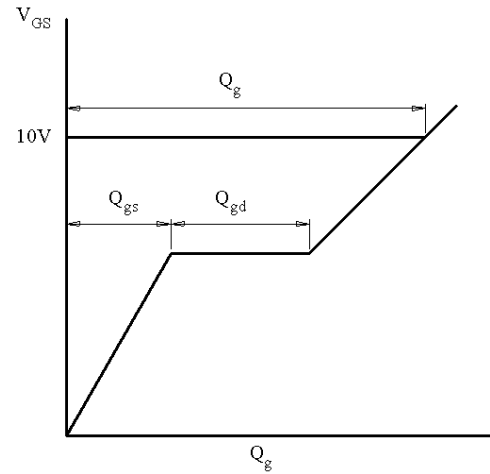
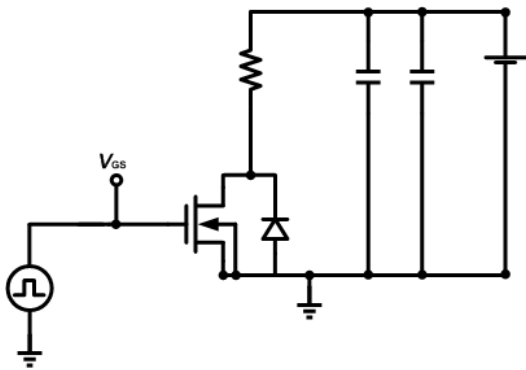
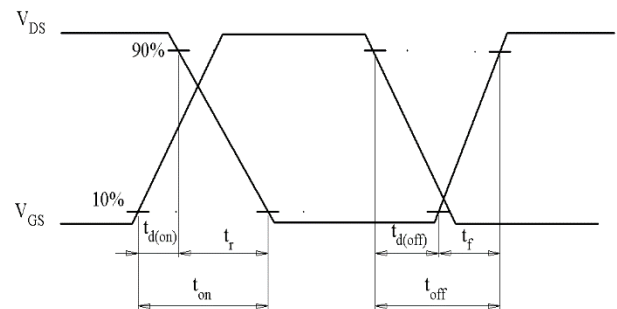
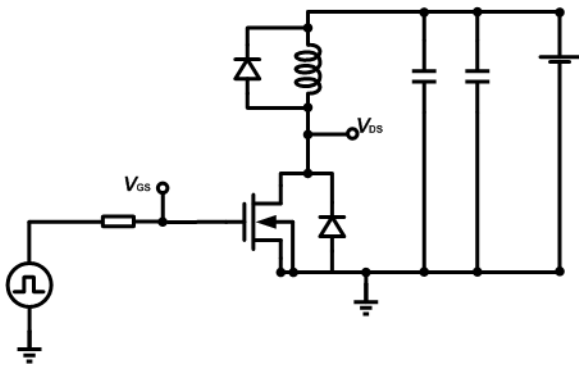
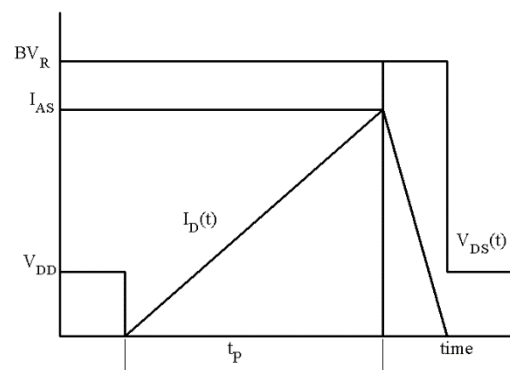
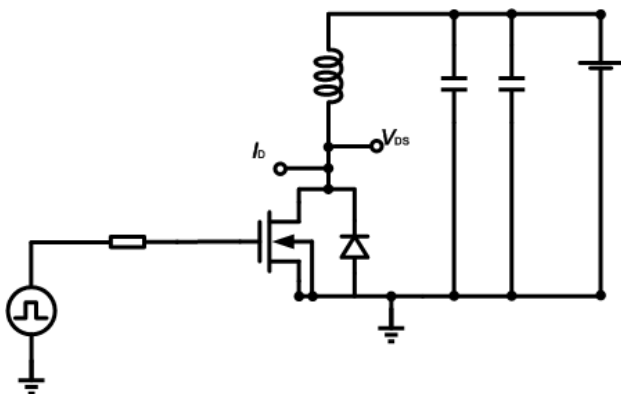
**Figure 18: On-State Resistance Vs Gate-Source Voltage**


$$R_{DS(ON)}=f(V_{GS}); T_j=25^{\circ}C$$

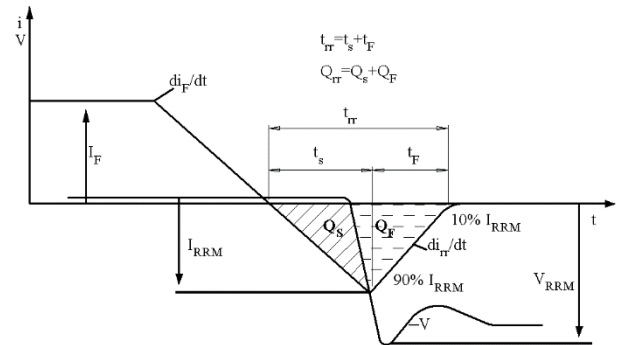
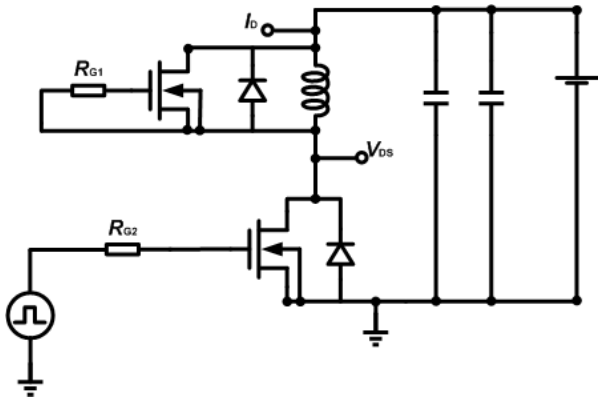
Figure 19: Safe Operating Area2

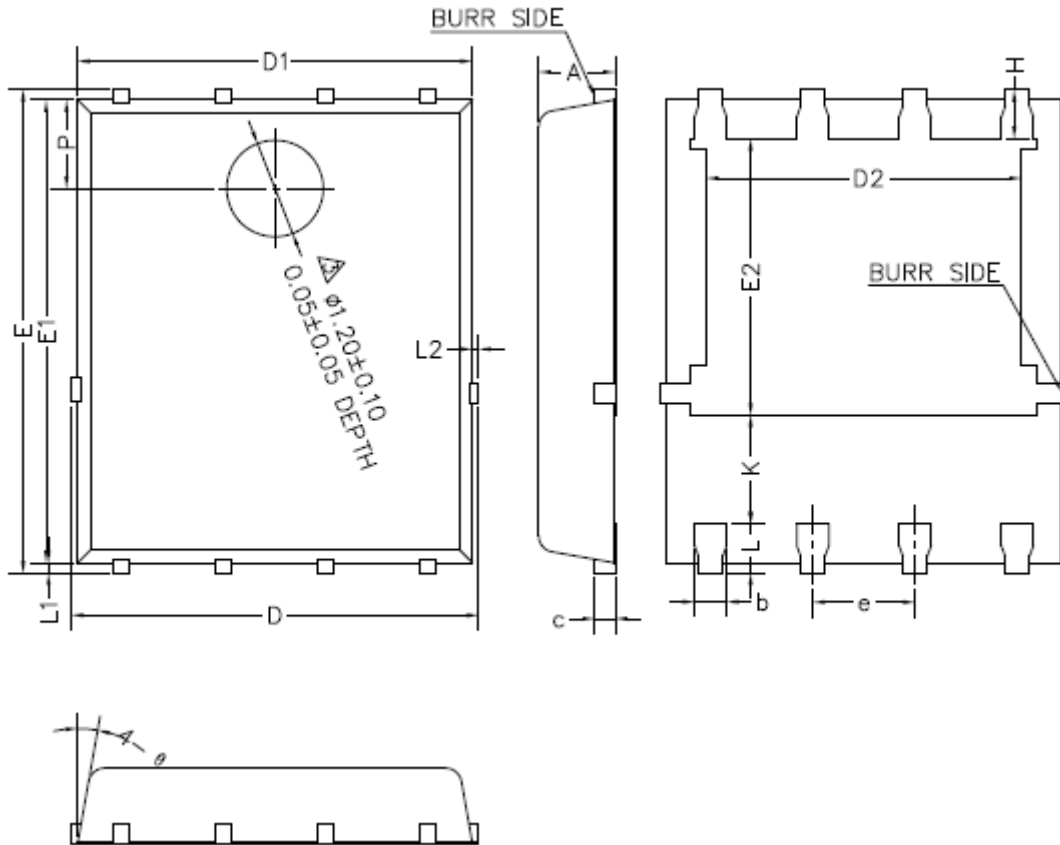




**Test Circuits**
**1. Gate Charge Test Circuit & Waveform**

**2. Switch Time Test Circuit**

**3. Unclamped Inductive Switching Test Circuit & Waveforms**


**4. Test Circuit and Waveform for Diode Characteristics**



**Mechanical Dimension**
**PDFN5\*6-8**
**Unit: mm**


Symbol	Dimensions(mm)		
	Min.	Typ.	Max.
A	0.90	1.10	1.20
b	0.35	0.40	0.45
c	0.21	0.25	0.34
D			5.10
D1	4.80	4.90	5.00
D2	3.91	4.01	4.11
e	1.17	1.27	1.37
E	5.90	6.00	6.10
E1	5.70	5.75	5.80
E2	3.34	3.44	3.54
H	0.51	0.61	0.71
K	1.10		
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
L2			0.10
P	1.00	1.10	1.20
θ	8°	10°	12°



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